



LIST OF REFERENCES ARRANGED BY APPLICANT (Use several sheets if necessary)		ATTY. DOCKET NO.:	APPLICATION NO.:
		88265-7228	10/661,397
		APPLICANT:	Zheng et al.
		FILING DATE:	September 11, 2003
GROUP: 1761			

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
VMW	AA	5,922,380	07/1999	Takihara	A23C	009/14	
VMW	AB	5,888,562	03/1999	Hansen et al.	A23G	1/00	
VMW	AC	5,364,555	11/1994	Zenner et al.	252	188.28	
VMW	AD	4,897,273	01/1990	Kotaki et al.	426	118	
VMW	AE	4,539,216	09/1985	Tsc	426	597	
VMW	AF	4,378,380	03/1983	Scarpellino et al.	A23L	1/234	
VMW	AG	4,287,995	09/1981	Moriya	215	228	
VMW	AH	3,540,889	11/1970	Clinton et al.	99	71	
VMW	AI	3,482,987	12/1969	Pitchon et al.	426	460	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
					YES	NO	
VMW	AJ	EP 0861596	09/1998	EUROPE			X
VMW	AK	EP0328336	08/1989	EUROPE			X
VMW	AL	WO9518540	07/1995	PCT			X
VMW	AM	WO9611861	04/1996	PCT			X
VMW	AN	WO 03 101216	12/2003	PCT			
VMW	AO	08196212 English Abstract	08/1996	Japan			X
VMW	AP	62278948 English Abstract	12/1987	Japan			X
VMW	AQ	08-182486 English Abstract	12/1987	Japan			X
VMW	AR	640241	07/1950	Great Britain			X
VMW	AS	44914 English Abstract		Hungary			X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

VMW	AT	Holscher, W. et al, XP008007644, "Investigations of Roasted Coffee Freshness With An Improved Headspace Technique-Aromafrische Mittels Einer Vergesserten Headspace-Methodik", Forschung, vol. 195, no. 1, 1992, pages 33-38
VMW	AU	Semmelroch, P. et al., XP000602989 "Analysis of Roasted Coffee Powders And Brews By Gas Chromatography-Olfactometry of Headspace Samples" Lebensmittel Wissenschaft Und Technologies, vol. 28, no. 3, 1995, pages 310-313

EXAMINER

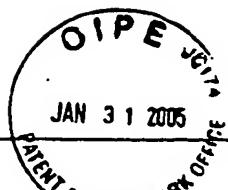
DATE CONSIDERED

Leslie Wong

6/16/04 4/21/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>					ATTY. DOCKET NO.:	APPLICATION SERIAL NO.:	
					88265-7228	10/661 397	
					APPLICANT: Ying Zheng et al.		
					FILING DATE:	GROUP:	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
LAW	AA	2,892,718	6/1959	Irwin M. Stone	99	48	
WAW	AB	3,421,906	1/1-69	Ismar M. Reich et al.	99	152	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES <input type="checkbox"/> NO <input type="checkbox"/>
AW	AC	0 277 688	10/1988	EUROPE			X
WAW	AD	0 934 702	11/1999	EUROPE			X
WAW	AE	0 963 706	12/1999	EUROPE			X
WAW	AF	JP 08182486 (with English Abstract)	7/1996	JAPAN			X
		CN 1109277 (with English Abstract)	10/1995	CHINA			X
WAW	AH	WP00/69274	11/2000	PCT			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			
Leslie Wong				6/10/04, 4/29/05			
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	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
UAW	AI	1109277	04/1995	China (abstract)				X
UAW	AJ	08-182486 English Abstract	12/1987	Japan				X
	AK							
	AL							
	AM							
	AN							
	AO							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AP	
AQ	

EXAMINER	DATE CONSIDERED
Leslie Wong	4/27/05

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